

<b>Notice of References Cited</b>	Application/Control No. 10/537,470	Applicant(s)/Patent Under Reexamination YANO ET AL.	
	Examiner Hieu P. Nguyen	Art Unit 2817	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,862,461	01-1999	Yoshizawa et al.	455/127.3
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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